

<b>Notice of References Cited</b>	Application/Control No. 10/067,425	Applicant(s)/Patent Under Reexamination VAN VEEN ET AL.	
	Examiner Scott B. Geyer	Art Unit 2829	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,492,737	12-2002	Imasu et al.	257/778
	C	US-6,225,206	05-2001	Jimarez et al.	438/616
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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